- **State-of-the-Art *EPIC*-II*B*™ BiCMOS Design Significantly Reduces Power Dissipation**

- **Latch-Up Performance Exceeds 500 mA Per JEDEC Standard JESD-17**

- **ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)**

- **Typical V_{OLP} (Output Ground Bounce) < 1 V at V_{CC} = 5 V, T_A = 25°C**

- **High-Drive Outputs (–32-mA I_{OH}, 64-mA I_{OL})**

- **Package Options Include Plastic Small-Outline (DW), Shrink Small-Outline (DB), and Thin Shrink Small-Outline (PW) Packages, Ceramic Chip Carriers (FK), Plastic (N) and Ceramic (J) DIPs, and Ceramic Flat (W) Package**
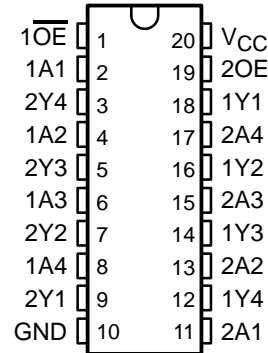
SN54ABT241 . . . J OR W PACKAGE
SN74ABT241A . . . DB, DW, N, OR PW PACKAGE
(TOP VIEW)

1$\overline{OE}$	1 20	V_{CC}
1A1	2 19	2OE
2Y4	3 18	1Y1
1A2	4 17	2A4
2Y3	5 16	1Y2
1A3	6 15	2A3
2Y2	7 14	1Y3
1A4	8 13	2A2
2Y1	9 12	1Y4
GND	10 11	2A1

SN54ABT241 . . . FK PACKAGE
(TOP VIEW)

Top pins: 2Y4, 1A1, 1$\overline{OE}$, V_{CC}, 2OE (pins 3 2 1 20 19)

1A2 4	18 1Y1
2Y3 5	17 2A4
1A3 6	16 1Y2
2Y2 7	15 2A3
1A4 8	14 1Y3

Bottom pins: 2Y1, GND, 2A1, 1Y4, 2A2 (pins 9 10 11 12 13)

description

These octal buffers and line drivers are designed specifically to improve both the performance and density of 3-state memory address drivers, clock drivers, and bus-oriented receivers and transmitters. Together with the SN54ABT240, SN74ABT240A, and 'ABT244A, these devices provide the choice of selected combinations of inverting and noninverting outputs, symmetrical active-low output-enable ($\overline{OE}$) inputs, and complementary OE and $\overline{OE}$ inputs.
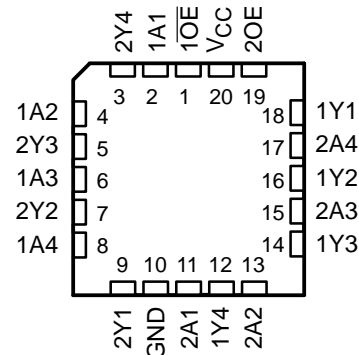
To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver. OE should be tied to GND through a pulldown resistor; the minimum value of the resistor is determined by the current-sourcing capability of the driver.

The SN54ABT241 is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74ABT241A is characterized for operation from –40°C to 85°C.

EPIC-IIB is a trademark of Texas Instruments Incorporated.

TEXAS INSTRUMENTS

POST OFFICE BOX 655303 ● DALLAS, TEXAS 75265

FUNCTION TABLES

INPUTS		OUTPUT
1OE	1A	1Y
L	H	H
L	L	L
H	X	Z

INPUTS		OUTPUT
2OE	2A	2Y
H	H	H
H	L	L
L	X	Z

logic symbol†
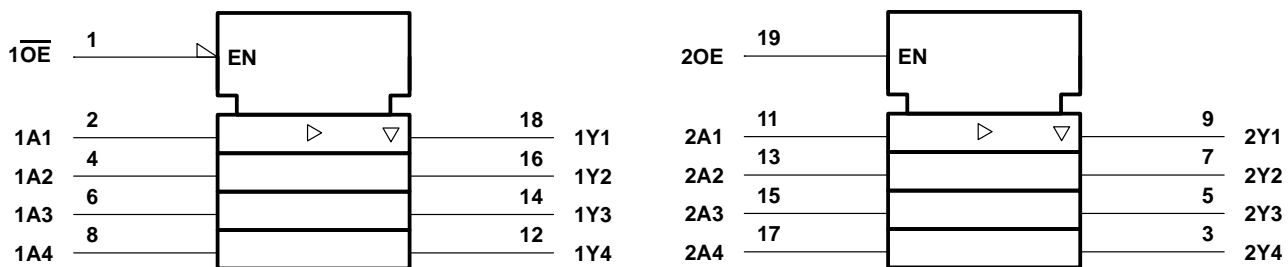
† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)

TEXAS
INSTRUMENTS
POST OFFICE BOX 655303 ● DALLAS, TEXAS 75265

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V_{CC}	−0.5 V to 7 V
Input voltage range, V_I (see Note 1)	−0.5 V to 7 V
Voltage range applied to any output in the high or power-off state, V_O	−0.5 V to 5.5 V
Current into any output in the low state, I_O: SN54ABT241	96 mA
SN74ABT241A	128 mA
Input clamp current, I_{IK} ($V_I < 0$)	−18 mA
Output clamp current, I_{OK} ($V_O < 0$)	−50 mA
Package thermal impedance, θ_{JA} (see Note 2): DB package	115°C/W
DW package	97°C/W
N package	67°C/W
PW package	128°C/W
Storage temperature range, T_{stg}	−65°C to 150°C

† Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
2. The package thermal impedance is calculated in accordance with EIA/JEDEC Std JESD51, except for through-hole packages, which use a trace length of zero.

recommended operating conditions (see Note 3)

			SN54ABT241		SN74ABT241A		UNIT
			MIN	MAX	MIN	MAX	
V_{CC}	Supply voltage		4.5	5.5	4.5	5.5	V
V_{IH}	High-level input voltage		2		2		V
V_{IL}	Low-level input voltage			0.8		0.8	V
V_I	Input voltage		0	V_{CC}	0	V_{CC}	V
I_{OH}	High-level output current			−24		−32	mA
I_{OL}	Low-level output current			48		64	mA
$\Delta t/\Delta v$	Input transition rise or fall rate	Outputs enabled		5		5	ns/V
T_A	Operating free-air temperature		−55	125	−40	85	°C

NOTE 3: Unused inputs must be held high or low to prevent them from floating.

TEXAS INSTRUMENTS

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		$T_A = 25°C$ MIN	TYP†	MAX	SN54ABT241 MIN	MAX	SN74ABT241A MIN	MAX	UNIT
V_{IK}		$V_{CC} = 4.5$ V,	$I_I = -18$ mA			−1.2		−1.2		−1.2	V
V_{OH}		$V_{CC} = 4.5$ V,	$I_{OH} = -3$ mA	2.5			2.5		2.5		V
		$V_{CC} = 5$ V,	$I_{OH} = -3$ mA	3			3		3		
		$V_{CC} = 4.5$ V	$I_{OH} = -24$ mA	2			2				
			$I_{OH} = -32$ mA	2*					2		
V_{OL}		$V_{CC} = 4.5$ V	$I_{OL} = 48$ mA			0.55		0.55			V
			$I_{OL} = 64$ mA			0.55*				0.55	
V_{hys}					100						mV
I_I		$V_{CC} = 5.5$ V,	$V_I = V_{CC}$ or GND			±1		±1		±1	µA
I_{OZH}		$V_{CC} = 5.5$ V,	$V_O = 2.7$ V			10		10		10	µA
I_{OZL}		$V_{CC} = 5.5$ V,	$V_O = 0.5$ V			−10		−10		−10	µA
I_{off}		$V_{CC} = 0$,	V_I or $V_O \leq 4.5$ V			±100				±100	µA
I_{CEX}		$V_{CC} = 5.5$ V, $V_O = 5.5$ V	Outputs high			50		50		50	µA
I_O‡		$V_{CC} = 5.5$ V,	$V_O = 2.5$ V	−50	−100	−180	−50	−180	−50	−180	mA
I_{CC}		$V_{CC} = 5.5$ V, $I_O = 0$, $V_I = V_{CC}$ or GND	Outputs high		1	250		250		250	µA
			Outputs low		24	30		30		30	mA
			Outputs disabled		0.5	250		250		250	µA
ΔI_{CC}§	Data inputs	$V_{CC} = 5.5$ V, One input at 3.4 V, Other inputs at V_{CC} or GND	Outputs enabled			1.5		1.5		1.5	mA
			Outputs disabled			0.05		0.05		0.05	
	Control inputs	$V_{CC} = 5.5$ V, One input at 3.4 V, Other inputs at V_{CC} or GND				1.5		1.5		1.5	
C_i		$V_I = 2.5$ V or 0.5 V			4						pF
C_o		$V_O = 2.5$ V or 0.5 V			5.5						pF

* On products compliant to MIL-PRF-38535, this parameter does not apply.
† All typical values are at $V_{CC} = 5$ V.
‡ Not more than one output should be tested at a time, and the duration of the test should not exceed one second.
§ This is the increase in supply current for each input that is at the specified TTL voltage level rather than V_{CC} or GND.

TEXAS INSTRUMENTS

POST OFFICE BOX 655303 ● DALLAS, TEXAS 75265

switching characteristics over recommended ranges of supply voltage and operating free-air temperature, C_L = 50 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	SN54ABT241 V_{CC} = 5 V, T_A = 25°C					UNIT
			MIN	TYP	MAX	MIN	MAX	
t_{PLH}	A	Y	1	2.6	4.1	0.8	5.3	ns
t_{PHL}			1	2.9	4.2	0.8	5	
t_{PZH}	$\overline{OE}$ or OE	Y	1.1	4.8	6.3	1	7	ns
t_{PZL}			1.3	4.3	5.8	1	7	
t_{PHZ}	$\overline{OE}$ or OE	Y	1.1	4.6	6.1	0.8	7.9	ns
t_{PLZ}			1	3.9	5.4	0.8	6.2	

switching characteristics over recommended ranges of supply voltage and operating free-air temperature, C_L = 50 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	SN74ABT241A V_{CC} = 5 V, T_A = 25°C					UNIT
			MIN	TYP	MAX	MIN	MAX	
t_{PLH}	A	Y	1	2.6	4.1	1	4.6	ns
t_{PHL}			1	2.9	4.4	1	4.6	
t_{PZH}	$\overline{OE}$ or OE	Y	1.1	4.8	6.3	1.1	6.8	ns
t_{PZL}			1.3	4.3	5.8	1.3	6.8	
t_{PHZ}	$\overline{OE}$ or OE	Y	1.6	4.6	6.1	1.6	7.1	ns
t_{PLZ}			1	3.9	5.4	1	5.9	

TEXAS
INSTRUMENTS

PARAMETER MEASUREMENT INFORMATION
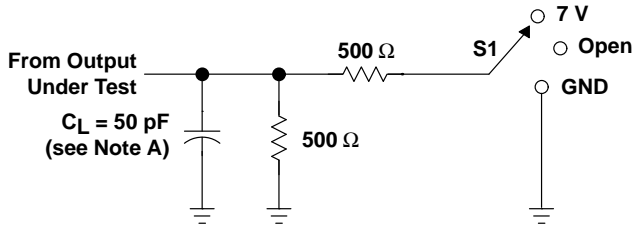
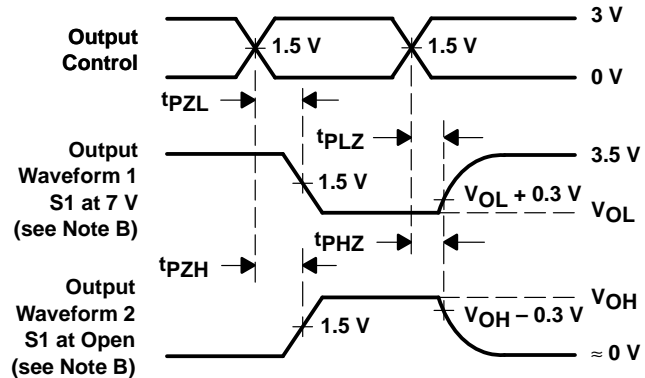| TEST	S1
t_{PLH}/t_{PHL}	Open
t_{PLZ}/t_{PZL}	7 V
t_{PHZ}/t_{PZH}	Open

LOAD CIRCUIT
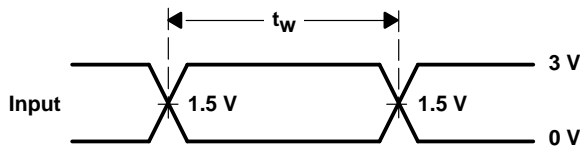
VOLTAGE WAVEFORMS
PULSE DURATION
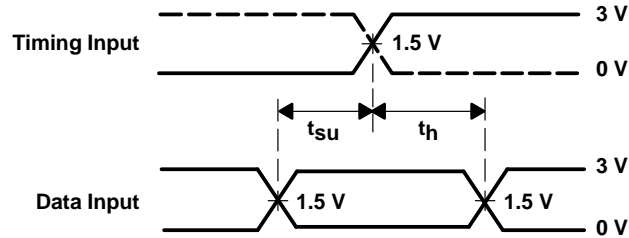
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES
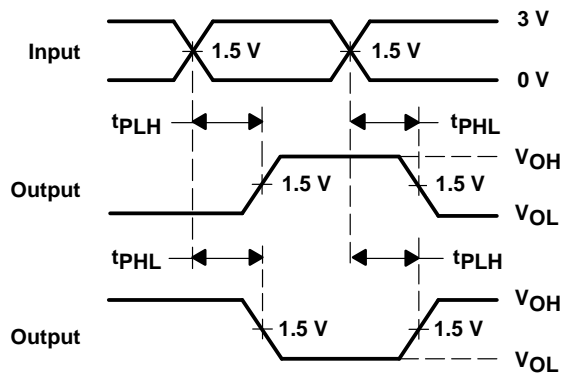
VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES
INVERTING AND NONINVERTING OUTPUTS

VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES
LOW- AND HIGH-LEVEL ENABLING

NOTES: A. C_L includes probe and jig capacitance.
      B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control.
         Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
      C. All input pulses are supplied by generators having the following characteristics: PRR ≤ 10 MHz, Z_O = 50 Ω, t_r ≤ 2.5 ns, t_f ≤ 2.5 ns.
      D. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

IMPORTANT NOTICE

Texas Instruments (TI) reserves the right to make changes to its products or to discontinue any semiconductor product or service without notice, and advises its customers to obtain the latest version of relevant information to verify, before placing orders, that the information being relied on is current.

TI warrants performance of its semiconductor products and related software to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

Certain applications using semiconductor products may involve potential risks of death, personal injury, or severe property or environmental damage ("Critical Applications").

TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, INTENDED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT APPLICATIONS, DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS.

Inclusion of TI products in such applications is understood to be fully at the risk of the customer. Use of TI products in such applications requires the written approval of an appropriate TI officer. Questions concerning potential risk applications should be directed to TI through a local SC sales office.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards should be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance, customer product design, software performance, or infringement of patents or services described herein. Nor does TI warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used.